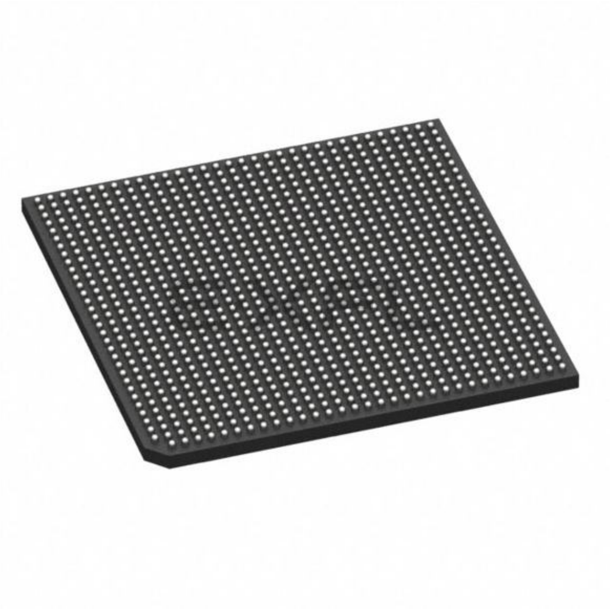
NXP USA Inc. - MPC8572EPXARLB Datasheet



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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.067GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	1023-BFBGA, FCBGA
Supplier Device Package	1023-FCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8572epxarlb

the upper and lower words of the 64-bit GPRs as they are defined by the SPE APU.
— Embedded vector and scalar single-precision floating-point APUs. Provide an instruction set for single-precision (32-bit) floating-point instructions.
— Double-precision floating-point APU. Provides an instruction set for double-precision (64-bit) floating-point instructions that use the 64-bit GPRs.
— 36-bit real addressing
— Memory management unit (MMU). Especially designed for embedded applications. Supports 4-Kbyte to 4-Gbyte page sizes.
— Enhanced hardware and software debug support
— Performance monitor facility that is similar to, but separate from, the MPC8572E performance monitor

The e500 defines features that are not implemented on this device. It also generally defines some features that this device implements more specifically. An understanding of these differences can be critical to ensure proper operation.

- 1 Mbyte L2 cache/SRAM
  — Shared by both cores.
  — Flexible configuration and individually configurable per core.
  — Full ECC support on 64-bit boundary in both cache and SRAM modes
  — Cache mode supports instruction caching, data caching, or both.
  — External masters can force data to be allocated into the cache through programmed memory ranges or special transaction types (stashing).
    – 1, 2, or 4 ways can be configured for stashing only.
  — Eight-way set-associative cache organization (32-byte cache lines)
  — Supports locking entire cache or selected lines. Individual line locks are set and cleared through Book E instructions or by externally mastered transactions.
  — Global locking and Flash clearing done through writes to L2 configuration registers
  — Instruction and data locks can be Flash cleared separately.
  — Per-way allocation of cache region to a given processor.
  — SRAM features include the following:
    – 1, 2, 4, or 8 ways can be configured as SRAM.
    – I/O devices access SRAM regions by marking transactions as snoopable (global).
    – Regions can reside at any aligned location in the memory map.
    – Byte-accessible ECC is protected using read-modify-write transaction accesses for smaller-than-cache-line accesses.
- e500 coherency module (ECM) manages core and intrasystem transactions
- Address translation and mapping unit (ATMU)
  — Twelve local access windows define mapping within local 36-bit address space.
  — Inbound and outbound ATMUs map to larger external address spaces.

- Regular expression (regex) pattern matching
  - Built-in case insensitivity, wildcard support, no pattern explosion
  - Cross-packet pattern detection
  - Fast pattern database compilation and fast incremental updates
  - 16000 patterns, each up to 128 bytes in length
  - Patterns can be split into 256 sets, each of which can contain 16 subsets
- Stateful rule engine enables hardware execution of state-aware logic when a pattern is found
  - Useful for contextual searches, multi-pattern signatures, or for performing additional checks after a pattern is found
  - Capable of capturing and utilizing data from the data stream (such as LENGTH field) and using that information in subsequent pattern searches (for example, positive match only if pattern is detected within the number of bytes specified in the LENGTH field)
  - 8192 stateful rules
- Deflate engine
  - Supports decompression of DEFLATE compression format including zlib and gzip
  - Can work independently or in conjunction with the Pattern Matching Engine (that is decompressed data can be passed directly to the Pattern Matching Engine without further software involvement or memory copying)

• Two Table Lookup Units (TLU)
  - Hardware-based lookup engine offloads table searches from e500 cores
  - Longest prefix match, exact match, chained hash, and flat data table formats
  - Up to 32 tables, with each table up to 16M entries
  - 32-, 64-, 96-, or 128-bit keys
• Two I^2C controllers
  - Two-wire interface
  - Multiple master support
  - Master or slave I^2C mode support
  - On-chip digital filtering rejects spikes on the bus
• Boot sequencer
  - Optionally loads configuration data from serial ROM at reset the I^2C interface
  - Can be used to initialize configuration registers and/or memory
  - Supports extended I^2C addressing mode
  - Data integrity checked with preamble signature and CRC
• DUART
  - Two 4-wire interfaces (SIN, SOUT, $\overline{RTS}$, $\overline{CTS}$)
  - Programming model compatible with the original 16450 UART and the PC16550D
• Enhanced local bus controller (eLBC)

Table 17. DDR2 and DDR3 SDRAM Interface Input AC Timing Specifications

At recommended operating conditions with GV_{DD} of 1.8 V ± 5% for DDR2 or 1.5 V ± 5% for DDR3.

Parameter	Symbol	Min	Max	Unit	Notes
Controller Skew for MDQS—MDQ/MECC	t_{CISKEW}	—	—	ps	1, 2
800 MHz	—	–200	200	—	—
667 MHz	—	–240	240	—	—
533 MHz	—	–300	300	—	—
400 MHz	—	–365	365	—	—

Note:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that is captured with MDQS[n]. This should be subtracted from the total timing budget.
2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called tDISKEW.This can be determined by the following equation: tDISKEW =+/–(T/4 – abs(tCISKEW)) where T is the clock period and abs(tCISKEW) is the absolute value of tCISKEW.

Figure 3 shows the DDR2 and DDR3 SDRAM interface input timing diagram.

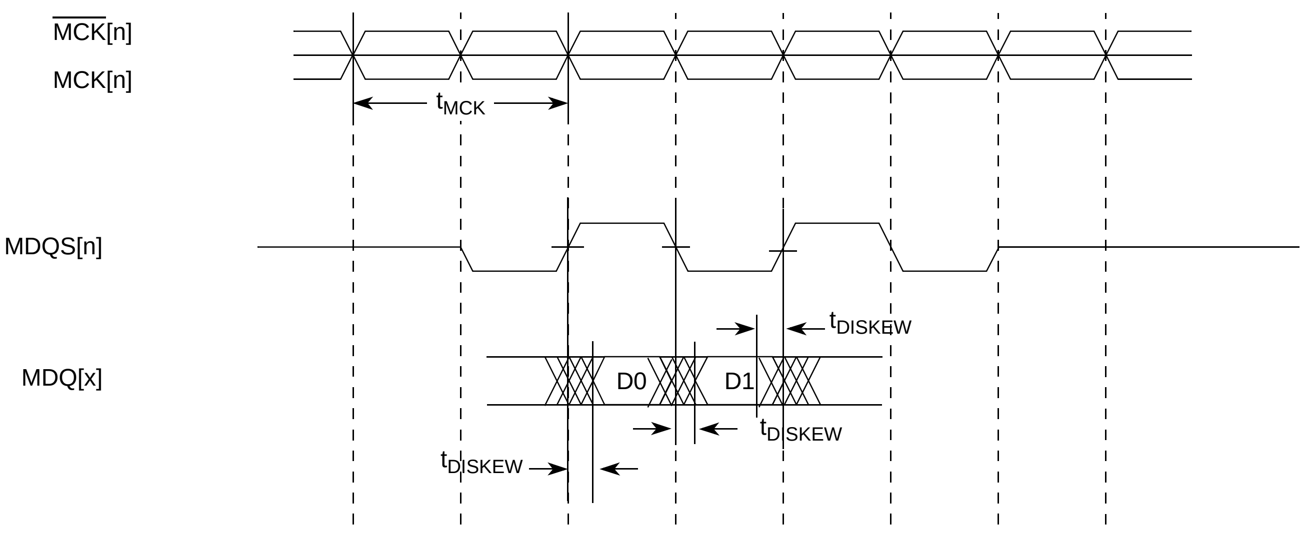


Figure 3. DDR2 and DDR3 SDRAM Interface Input Timing Diagram

6.2.2 DDR2 and DDR3 SDRAM Interface Output AC Timing Specifications

Table 18 contains the output AC timing targets for the DDR2 and DDR3 SDRAM interface.

Table 18. DDR2 and DDR3 SDRAM Interface Output AC Timing Specifications

At recommended operating conditions with GV_{DD} of 1.8 V ± 5% for DDR2 or 1.5 V ± 5% for DDR3.

Parameter	Symbol [1]	Min	Max	Unit	Notes
MCK[n] cycle time	t_{MCK}	2.5	5	ns	2
ADDR/CMD output setup with respect to MCK	t_{DDKHAS}			ns	3

Figure 6 provides the AC test load for the DDR2 and DDR3 Controller bus.

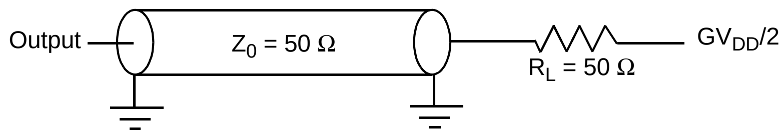
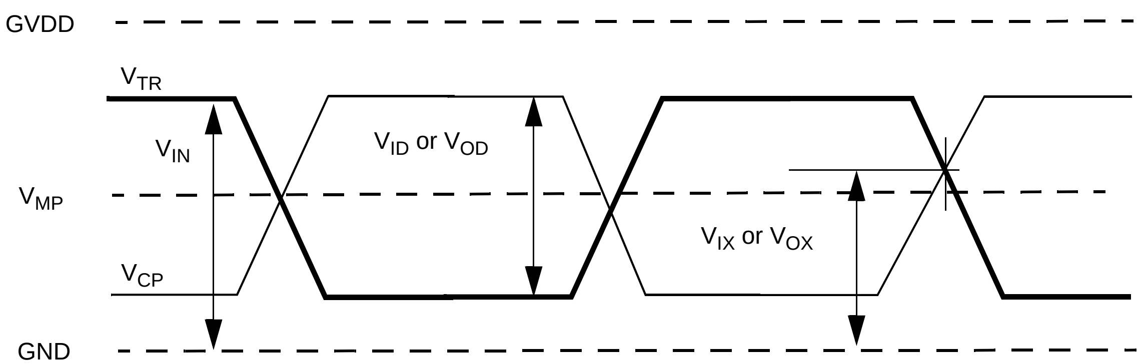


Figure 6. DDR2 and DDR3 Controller bus AC Test Load

6.2.3 DDR2 and DDR3 SDRAM Differential Timing Specifications

This section describes the DC and AC differential electrical specifications for the DDR2 and DDR3 SDRAM controller interface of the MPC8572E.



NOTE

VID specifies the input differential voltage |VTR -VCP| required for switching, where VTR is the true input signal (such as MCK or MDQS) and VCP is the complementary input signal (such as $\overline{\text{MCK}}$ or $\overline{\text{MDQS}}$).

Table 19 provides the differential specifications for the MPC8572E differential signals MDQS/$\overline{\text{MDQS}}$ and MCK/$\overline{\text{MCK}}$ when in DDR2 mode.

Table 19. DDR2 SDRAM Differential Electrical Characteristics

Parameter/Condition	Symbol	Min	Max	Unit	Notes
DC Input Signal Voltage	V_{IN}	–0.3	GV_{DD} + 0.3	V	—
DC Differential Input Voltage	V_{ID}	—	—	mV	—
AC Differential Input Voltage	V_{IDAC}	—	—	mV	—
DC Differential Output Voltage	V_{OH}	—	—	mV	—
AC Differential Output Voltage	V_{OHAC}	JEDEC: 0.5	JEDEC: GV_{DD} + 0.6	V	—
AC Differential Cross-point Voltage	V_{IXAC}	—	—	mV	—
Input Midpoint Voltage	V_{MP}	—	—	mV	—

Figure 12 shows the MII transmit AC timing diagram.

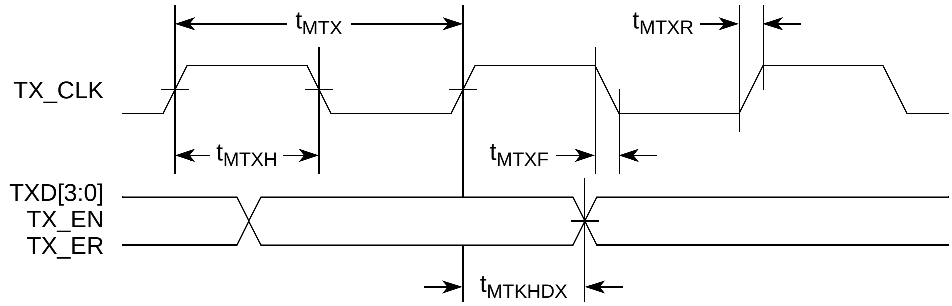


Figure 12. MII Transmit AC Timing Diagram

8.2.3.2 MII Receive AC Timing Specifications

Table 30 provides the MII receive AC timing specifications.

Table 30. MII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX} [2]	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise (20%-80%)	t_{MRXR} [2]	1.0	—	4.0	ns
RX_CLK clock fall time (80%-20%)	t_{MRXF} [2]	1.0	—	4.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.

Figure 13 provides the AC test load for eTSEC.

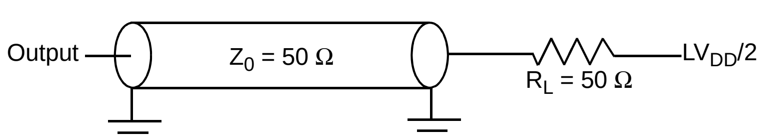


Figure 13. eTSEC AC Test Load

8.3.4 SGMII AC Timing Specifications

This section describes the SGMII transmit and receive AC timing specifications. Transmitter and receiver characteristics are measured at the transmitter outputs (SD2_TX[n] and $\overline{\text{SD2\_TX}}$[n]) or at the receiver inputs (SD2_RX[n] and $\overline{\text{SD2\_RX}}$[n]) as depicted in Figure 25, respectively.

8.3.4.1 SGMII Transmit AC Timing Specifications

Table 40 provides the SGMII transmit AC timing targets. A source synchronous clock is not provided.

Table 40. SGMII Transmit AC Timing Specifications

At recommended operating conditions with XV_{DD_SRDS2} = 1.1V ± 5%.

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic Jitter	JD	—	—	0.17	UI p-p	—
Total Jitter	JT	—	—	0.35	UI p-p	—
Unit Interval	UI	799.92	800	800.08	ps	1
V_{OD} fall time (80%-20%)	tfall	50	—	120	ps	—
V_{OD} rise time (20%-80%)	t_{rise}	50	—	120	ps	—

Notes:
1. Each UI is 800 ps ± 100 ppm.

8.3.4.2 SGMII Receive AC Timing Specifications

Table 41 provides the SGMII receive AC timing specifications. Source synchronous clocking is not supported. Clock is recovered from the data. Figure 24 shows the SGMII receiver input compliance mask eye diagram.

Table 41. SGMII Receive AC Timing Specifications

At recommended operating conditions with XV_{DD_SRDS2} = 1.1V ± 5%.

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic Jitter Tolerance	JD	0.37	—	—	UI p-p	1
Combined Deterministic and Random Jitter Tolerance	JDR	0.55	—	—	UI p-p	1
Sinusoidal Jitter Tolerance	JSIN	0.1	—	—	UI p-p	1
Total Jitter Tolerance	JT	0.65	—	—	UI p-p	1
Bit Error Ratio	BER	—	—	10^{-12}	—	—
Unit Interval	UI	799.92	800	800.08	ps	2
AC Coupling Capacitor	C_{TX}	5	—	200	nF	3

Notes:
1. Measured at receiver.
2. Each UI is 800 ps ± 100 ppm.
3. The external AC coupling capacitor is required. It is recommended to be placed near the device transmitter outputs.
4. See *RapidIO 1x/4x LP Serial Physical Layer Specification* for interpretation of jitter specifications.

Table 45. MII Management AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3 V ± 5% or 2.5 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit	Notes
ECn_MDIO to ECn_MDC setup time	t_{MDDVKH}	5	—	—	ns	—
ECn_MDIO to ECn_MDC hold time	t_{MDDXKH}	0	—	—	ns	—
ECn_MDC rise time	t_{MDCR}	—	—	10	ns	4
ECn_MDC fall time	t_{MDHF}	—	—	10	ns	4

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. This parameter is dependent on the eTSEC system clock speed, which is half of the Platform Frequency (f_{CCB}). The actual ECn_MDC output clock frequency for a specific eTSEC port can be programmed by configuring the MgmtClk bit field of MPC8572E's MIIMCFG register, based on the platform (CCB) clock running for the device. The formula is: Platform Frequency (CCB)/(2*Frequency Divider determined by MIICFG[MgmtClk] encoding selection). For example, if MIICFG[MgmtClk] = 000 and the platform (CCB) is currently running at 533 MHz, f_{MDC} = 533/(2*4*8) = 533/64 = 8.3 MHz. That is, for a system running at a particular platform frequency (f_{CCB}), the ECn_MDC output clock frequency can be programmed between maximum $f_{MDC} = f_{CCB}/64$ and minimum $f_{MDC} = f_{CCB}/448$. Refer to MPC8572E reference manual's MIIMCFG register section for more detail.
3. The maximum ECn_MDC output clock frequency is defined based on the maximum platform frequency for MPC8572E (600 MHz) divided by 64, while the minimum ECn_MDC output clock frequency is defined based on the minimum platform frequency for MPC8572E (400 MHz) divided by 448, following the formula described in Note 2 above. The typical ECn_MDC output clock frequency of 2.5 MHz is shown for reference purpose per IEEE 802.3 specification.
4. Guaranteed by design.
5. t_{plb_clk} is the platform (CCB) clock.

Figure 28 shows the MII management AC timing diagram.

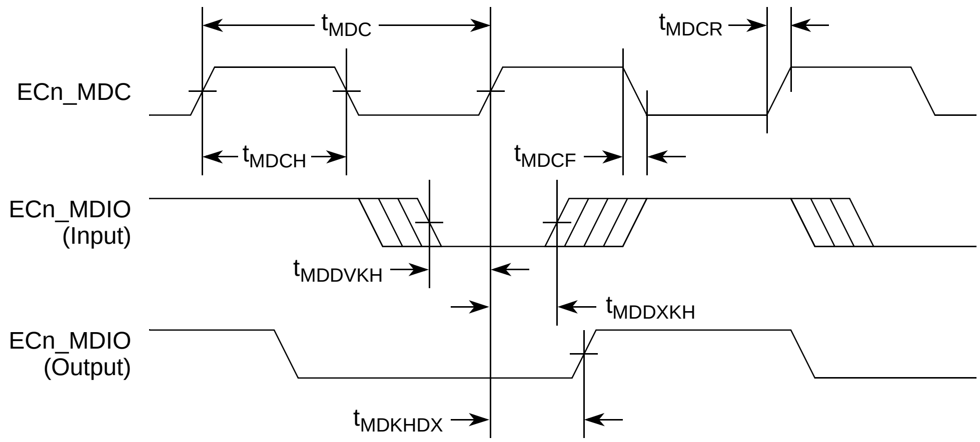


Figure 28. MII Management Interface Timing Diagram

Table 50. Local Bus General Timing Parameters (BV_{DD} = 2.5 V DC)—PLL Enabled (continued)

At recommended operating conditions with BV_{DD} of 2.5 V ± 5% (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.4	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.5	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.4	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.4	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.8	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.8	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.6	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.6	ns	5

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{(First\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(First\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 2.5-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Table 51 describes the general timing parameters of the local bus interface at BV_{DD} = 1.8 V DC

Table 51. Local Bus General Timing Parameters (BV_{DD} = 1.8 V DC)—PLL Enabled

At recommended operating conditions with BV_{DD} of 1.8 V ± 5%

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	6.67	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	$t_{LBKSKEW}$	—	150	ps	7, 8
Input setup to local bus clock (except $\overline{LGTA}$/LUPWAIT)	$t_{LBIVKH1}$	2.4	—	ns	3, 4
$\overline{LGTA}$/LUPWAIT input setup to local bus clock	$t_{LBIVKH2}$	1.9	—	ns	3, 4
Input hold from local bus clock (except $\overline{LGTA}$/LUPWAIT)	$t_{LBIXKH1}$	1.1	—	ns	3, 4

Figure 30 through Figure 35 show the local bus signals.

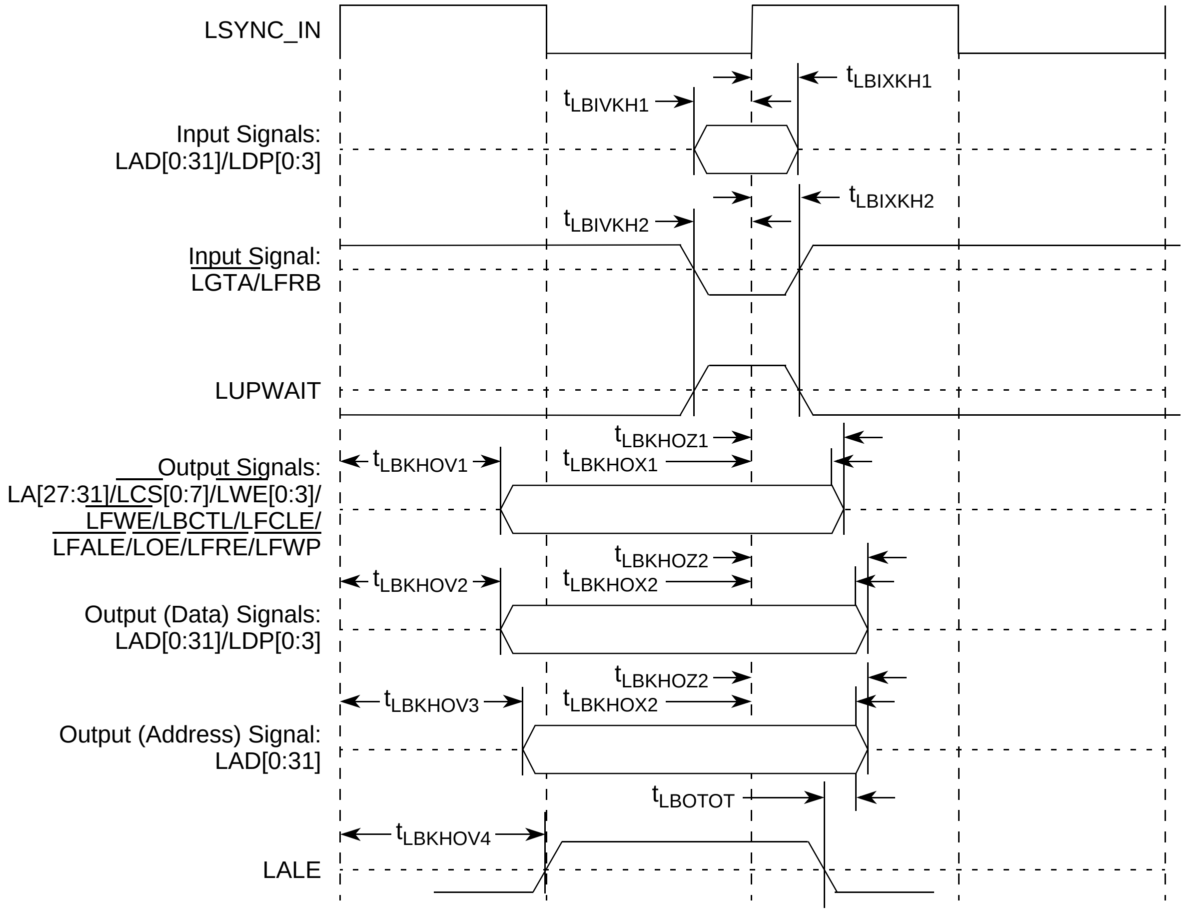


Figure 30. Local Bus Signals, Non-Special Signals Only (PLL Enabled)

Table 52 describes the general timing parameters of the local bus interface at BV_{DD} = 3.3 V DC with PLL disabled.

Table 52. Local Bus General Timing Parameters—PLL Bypassed

At recommended operating conditions with BV_{DD} of 3.3 V ± 5%

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	12	—	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
Internal launch/capture clock to LCLK delay	t_{LBKHKT}	2.3	4.0	ns	—
Input setup to local bus clock (except LGTA/LUPWAIT)	$t_{LBIVKH1}$	5.8	—	ns	4, 5
LGTA/LUPWAIT input setup to local bus clock	$t_{LBIVKL2}$	5.7	—	ns	4, 5
Input hold from local bus clock (except LGTA/LUPWAIT)	$t_{LBIXKH1}$	-1.3	—	ns	4, 5

Table 52. Local Bus General Timing Parameters—PLL Bypassed (continued)

At recommended operating conditions with BV_{DD} of 3.3 V ± 5%

Parameter	Symbol [1]	Min	Max	Unit	Notes
$\overline{LGTA}$/LUPWAIT input hold from local bus clock	$t_{LBIXKL2}$	-1.3	—	ns	4, 5
LALE output negation to high impedance for LAD/LDP (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKLOV1}$	—	–0.3	ns	
Local bus clock to data valid for LAD/LDP	$t_{LBKLOV2}$	—	–0.1	ns	4
Local bus clock to address valid for LAD	$t_{LBKLOV3}$	—	0.0	ns	4
Local bus clock to LALE assertion	$t_{LBKLOV4}$	—	0.0	ns	4
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKLOX1}$	–3.3	—	ns	4
Output hold from local bus clock for LAD/LDP	$t_{LBKLOX2}$	–3.3	—	ns	4
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKLOZ1}$	—	0.2	ns	7
Local bus clock to output high impedance for LAD/LDP	$t_{LBKLOZ2}$	—	0.2	ns	7

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(First two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(First two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to local bus clock for PLL bypass mode. Timings may be negative with respect to the local bus clock because the actual launch and capture of signals is done with the internal launch/capture clock, which precedes LCLK by t_{LBKHKT}.
3. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
4. All signals are measured from BVDD/2 of the rising edge of local bus clock for PLL bypass mode to 0.4 x BVDD of the signal in question for 3.3-V signaling levels.
5. Input timings are measured at the pin.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

NOTE

In PLL bypass mode, LCLK[n] is the inverted version of the internal clock with the delay of t_{LBKHKT}. In this mode, signals are launched at the rising edge of the internal clock and are captured at the falling edge of the internal clock with the exception of $\overline{LGTA}$/LUPWAIT (which is captured on the rising edge of the internal clock).

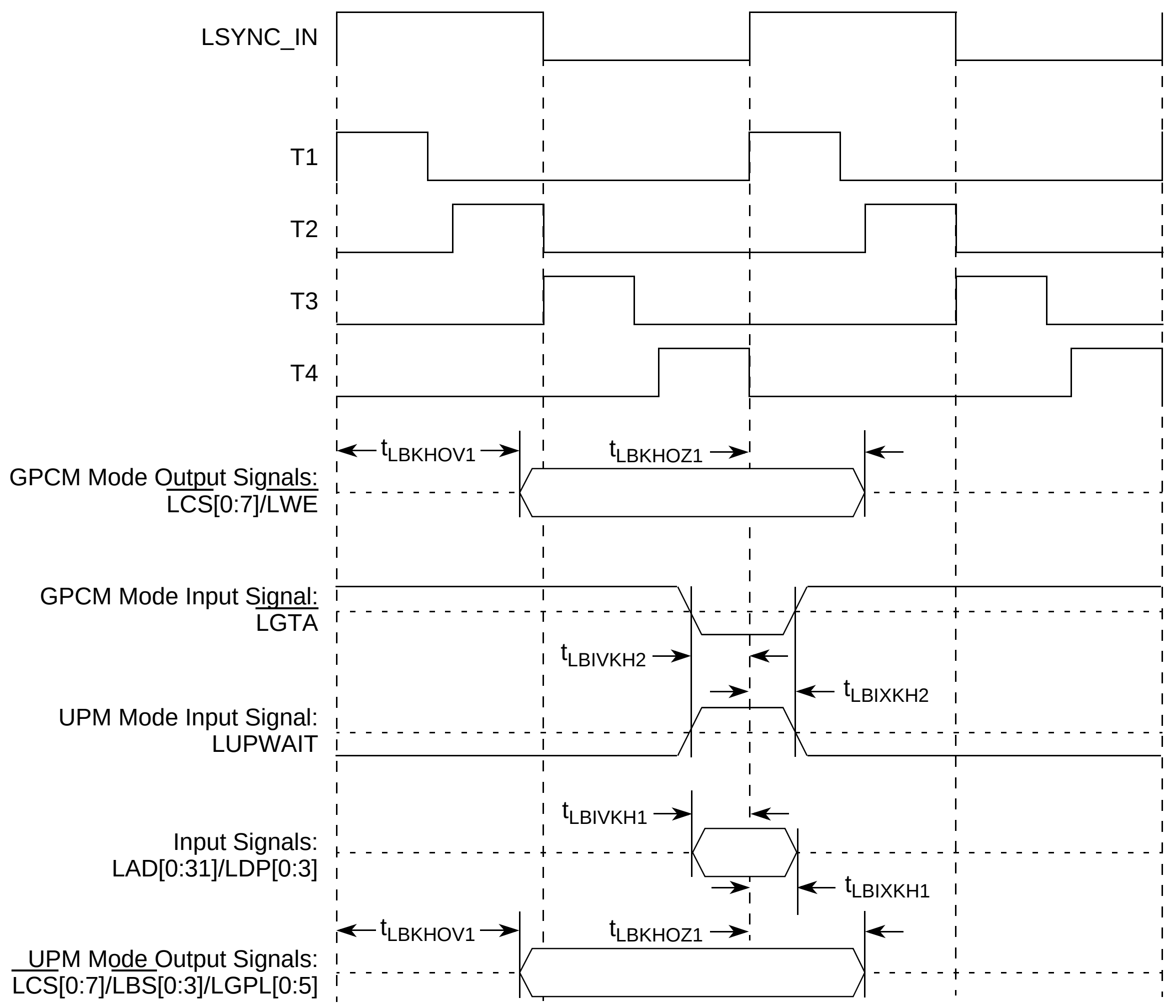
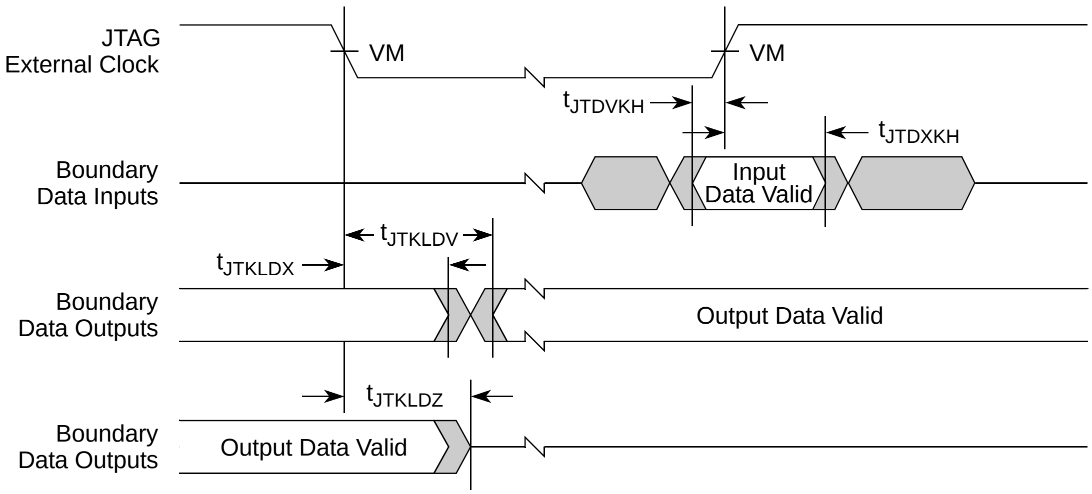


Figure 34. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 8 or 16 (PLL Enabled)

VM = Midpoint Voltage ($OV_{DD}/2$)

Figure 38. TRST Timing Diagram

Figure 39 provides the boundary-scan timing diagram.



VM = Midpoint Voltage ($OV_{DD}/2$)

Figure 39. Boundary-Scan Timing Diagram

13 I^2C

This section describes the DC and AC electrical characteristics for the I^2C interfaces of the MPC8572E.

13.1 I^2C DC Electrical Characteristics

Table 54 provides the DC electrical characteristics for the I^2C interfaces.

Table 54. I^2C DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V_{IH}	$0.7 \times OV_{DD}$	$OV_{DD} + 0.3$	V	—
Input low voltage level	V_{IL}	–0.3	$0.3 \times OV_{DD}$	V	—
Low level output voltage	V_{OL}	0	0.4	V	1
Pulse width of spikes which must be suppressed by the input filter	t_{I2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between $0.1 \times OV_{DD}$ and $0.9 \times OV_{DD}$(max))	I_I	–10	10	µA	3

Table 55. I²C AC Electrical Specifications (continued)

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%. All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 2).

Parameter	Symbol[1]	Min	Max	Unit
Capacitive load for each bus line	Cb	—	400	pF

Notes:

1. The symbols used for timing specifications herein follow the pattern $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the START condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the STOP condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time.
2. As a transmitter, the MPC8572E provides a delay time of at least 300 ns for the SDA signal (referred to the VIHmin of the SCL signal) to bridge the undefined region of the falling edge of SCL to avoid unintended generation of START or STOP condition. When the MPC8572E acts as the I2C bus master while transmitting, the MPC8572E drives both SCL and SDA. As long as the load on SCL and SDA are balanced, the MPC8572E would not cause unintended generation of START or STOP condition. Therefore, the 300 ns SDA output delay time is not a concern. If, under some rare condition, the 300 ns SDA output delay time is required for the MPC8572E as transmitter, application note AN2919 referred to in note 4 below is recommended.
3. The maximum t_{I2OVKL} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
4. The requirements for I²C frequency calculation must be followed. Refer to Freescale application note AN2919, *Determining the I²C Frequency Divider Ratio for SCL*.

Figure 40 provides the AC test load for the I²C.

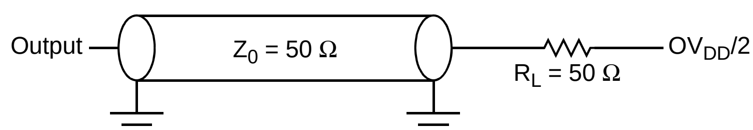


Figure 40. I²C AC Test Load

Figure 41 shows the AC timing diagram for the I²C bus.

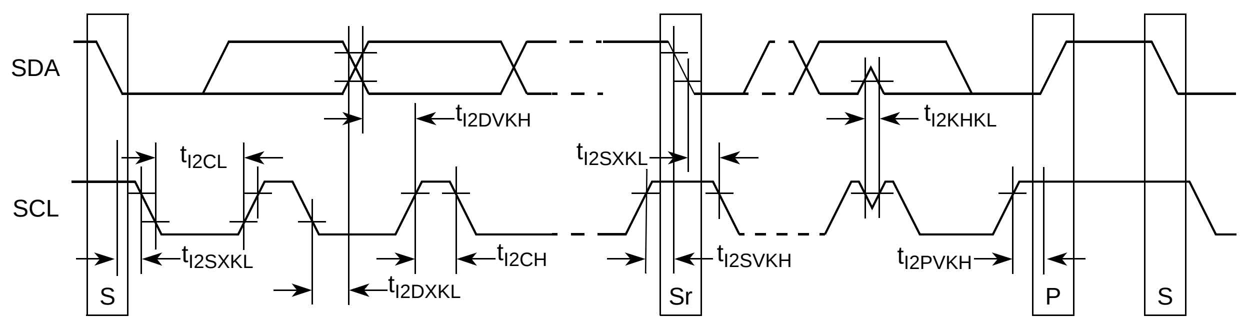


Figure 41. I²C Bus AC Timing Diagram

14 GPIO

This section describes the DC and AC electrical specifications for the GPIO interface of the MPC8572E.

14.1 GPIO DC Electrical Characteristics

Table 56 provides the DC electrical characteristics for the GPIO interface operating at BV_{DD} = 3.3 V DC.

Table 56. GPIO DC Electrical Characteristics (3.3 V DC)

Parameter	Symbol	Min	Max	Unit
Supply voltage 3.3V	BV_{DD}	3.13	3.47	V
High-level input voltage	V_{IH}	2	BV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.8	V
Input current (BV_{IN} [1] = 0 V or BV_{IN} = BV_{DD})	I_{IN}	—	±5	μA
High-level output voltage (BV_{DD} = min, I_{OH} = –2 mA)	V_{OH}	BV_{DD} – 0.2	—	V
Low-level output voltage (BV_{DD} = min, I_{OL} = 2 mA)	V_{OL}	—	0.2	V

Note:
1. Note that the symbol BV_{IN}, in this case, represents the BV_{IN} symbol referenced in Table 1.

Table 57 provides the DC electrical characteristics for the GPIO interface operating at BV_{DD} = 2.5 V DC.

Table 57. GPIO DC Electrical Characteristics (2.5 V DC)

Parameter	Symbol	Min	Max	Unit
Supply voltage 2.5V	BV_{DD}	2.37	2.63	V
High-level input voltage	V_{IH}	1.70	BV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.7	V
Input current (BV_{IN} [1] = 0 V or BV_{IN} = BV_{DD})	I_{IH}	—	10	μA
	I_{IL}		–15	
High-level output voltage (BV_{DD} = min, I_{OH} = –1 mA)	V_{OH}	2.0	BV_{DD} + 0.3	V
Low-level output voltage (BV_{DD} min, I_{OL} = 1 mA)	V_{OL}	GND – 0.3	0.4	V

Note:
1. The symbol BV_{IN}, in this case, represents the BV_{IN} symbol referenced in Table 1.

clock driver chip manufacturer to verify whether this connection scheme is compatible with a particular clock driver chip.

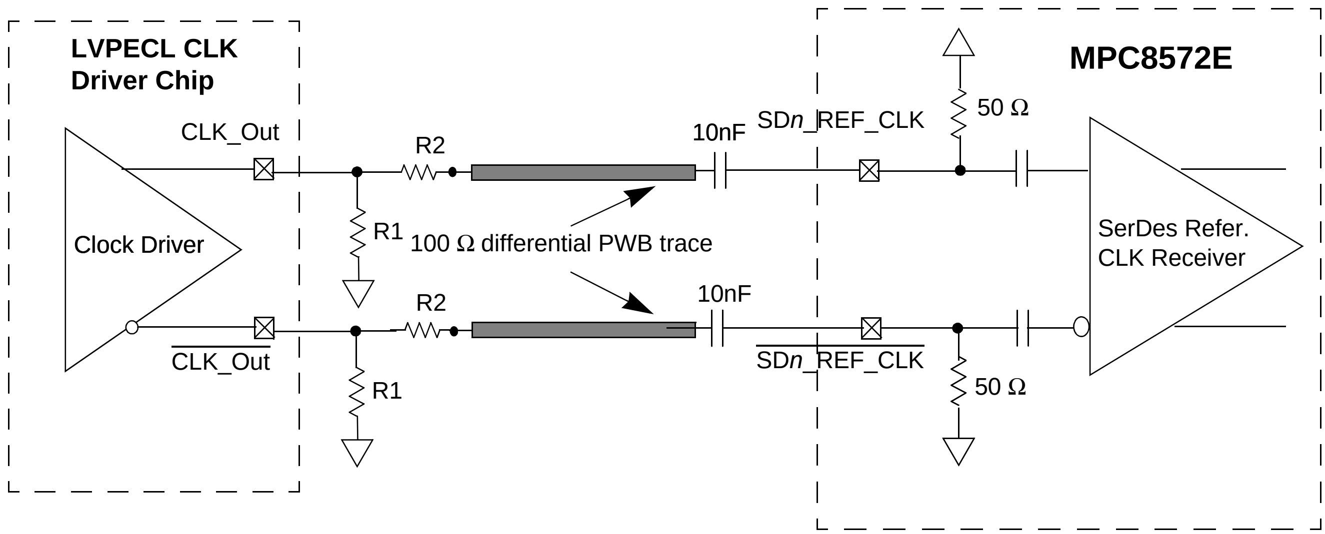


Figure 50. AC-Coupled Differential Connection with LVPECL Clock Driver (Reference Only)

Figure 51 shows the SerDes reference clock connection reference circuits for a single-ended clock driver. It assumes the DC levels of the clock driver are compatible with MPC8572E SerDes reference clock input's DC requirement.

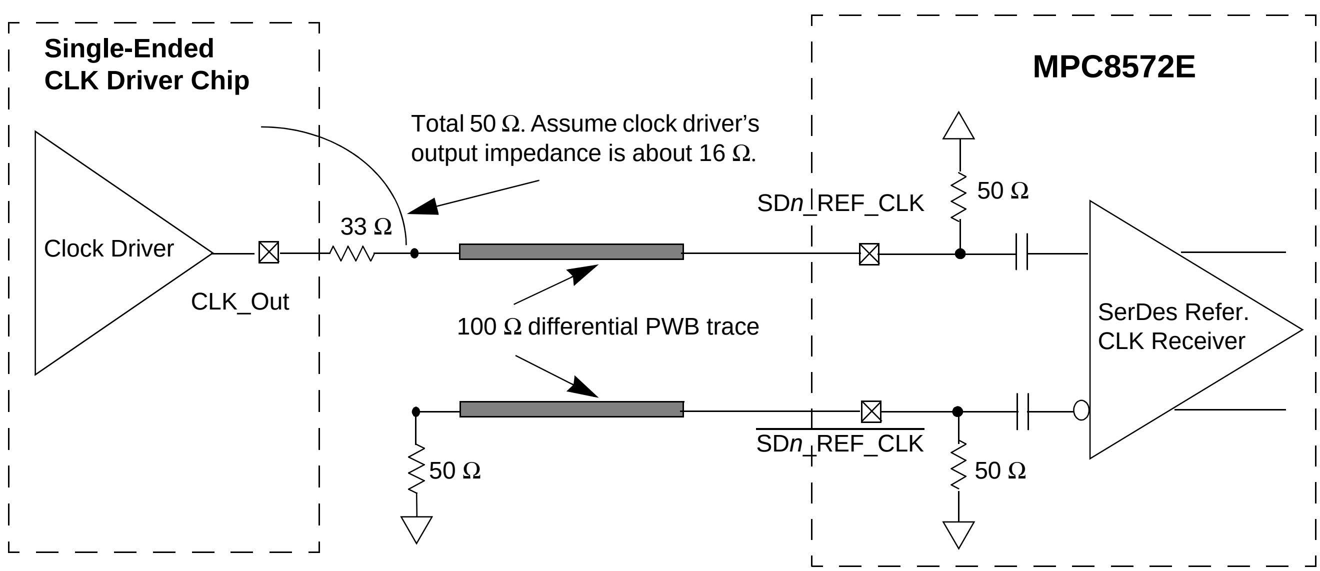


Figure 51. Single-Ended Connection (Reference Only)

15.2.4 AC Requirements for SerDes Reference Clocks

The clock driver selected should provide a high quality reference clock with low phase noise and cycle-to-cycle jitter. Phase noise less than 100KHz can be tracked by the PLL and data recovery loops and

Table 63. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nominal	Max	Units	Comments
$L_{RX\text{-}SKEW}$	Total Skew	—	—	20	ns	Skew across all lanes on a Link. This includes variation in the length of SKP ordered set (for example, COM and one to five SKP Symbols) at the RX as well as any delay differences arising from the interconnect itself.

Notes:
1. No test load is necessarily associated with this value.
2. Specified at the measurement point and measured over any 250 consecutive UIs. The test load in Figure 57 should be used as the RX device when taking measurements (also refer to the Receiver compliance eye diagram shown in Figure 56). If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as a reference for the eye diagram.
3. A $T_{RX\text{-}EYE}$ = 0.40 UI provides for a total sum of 0.60 UI deterministic and random jitter budget for the Transmitter and interconnect collected any 250 consecutive UIs. The $T_{RX\text{-}EYE\text{-}MEDIAN\text{-}to\text{-}MAX\text{-}JITTER}$ specification ensures a jitter distribution in which the median and the maximum deviation from the median is less than half of the total. UI jitter budget collected over any 250 consecutive TX UIs. It should be noted that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value. If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as the reference for the eye diagram.
4. The Receiver input impedance shall result in a differential return loss greater than or equal to 15 dB with the D+ line biased to 300 mV and the D- line biased to -300 mV and a common mode return loss greater than or equal to 6 dB (no bias required) over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements for is 50 ohms to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50 ohm probes - see Figure 57). Note: that the series capacitors CTX is optional for the return loss measurement.
5. Impedance during all LTSSM states. When transitioning from a Fundamental Reset to Detect (the initial state of the LTSSM) there is a 5 ms transition time before Receiver termination values must be met on all un-configured Lanes of a Port.
6. The RX DC Common Mode Impedance that exists when no power is present or Fundamental Reset is asserted. This helps ensure that the Receiver Detect circuit does not falsely assume a Receiver is powered on when it is not. This term must be measured at 300 mV above the RX ground.
7. It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function. Least squares and median deviation fits have worked well with experimental and simulated data.

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{D1\_MCAS}}$	Column Address Strobe	AC9	O	GV_{DD}	—
$\overline{\text{D1\_MRAS}}$	Row Address Strobe	AB12	O	GV_{DD}	—
D1_MCKE[0:3]	Clock Enable	M8, L9, T9, N8	O	GV_{DD}	11
$\overline{\text{D1\_MCS}}$[0:3]	Chip Select	AB9, AF10, AB11, AE11	O	GV_{DD}	—
D1_MCK[0:5]	Clock	V7, E13, AH11, Y9, F14, AG10	O	GV_{DD}	—
$\overline{\text{D1\_MCK}}$[0:5]	Clock Complements	Y10, E12, AH12, AA11, F13, AG11	O	GV_{DD}	—
D1_MODT[0:3]	On Die Termination	AD10, AF12, AC10, AE12	O	GV_{DD}	—
D1_MDIC[0:1]	Driver Impedance Calibration	E15, G14	I/O	GV_{DD}	25
DDR SDRAM Memory Interface 2					
D2_MDQ[0:63]	Data	A6, B7, C5, D5, A7, C8, D8, D6, C4, A3, D3, D2, B4, A4, B1, C1, E3, E1, G2, G6, D1, E4, G5, G3, J4, J2, P4, R5, H3, H1, N5, N3, Y6, Y4, AC3, AD2, V5, W5, AB2, AB3, AD5, AE3, AF6, AG7, AC4, AD4, AF4, AF7, AH5, AJ1, AL2, AM3, AH3, AH6, AM1, AL3, AK5, AL5, AJ7, AK7, AK4, AM4, AL6, AM7	I/O	GV_{DD}	—
D2_MECC[0:7]	Error Correcting Code	J5, H7, L7, N6, H4, H6, M4, M5	I/O	GV_{DD}	—
$\overline{\text{D2\_MAPAR\_ERR}}$	Address Parity Error	N1	I	GV_{DD}	—
D2_MAPAR_OUT	Address Parity Out	W2	O	GV_{DD}	—
D2_MDM[0:8]	Data Mask	A5, B3, F4, J1, AA4, AE5, AK1, AM5, K5	O	GV_{DD}	—
D2_MDQS[0:8]	Data Strobe	B6, C2, F5, L4, AB5, AF3, AL1, AM6, L6	I/O	GV_{DD}	—
$\overline{\text{D2\_MDQS}}$[0:8]	Data Strobe	C7, A2, F2, K3, AA5, AE6, AK2, AJ6, K6	I/O	GV_{DD}	—
D2_MA[0:15]	Address	W1, U4, U3, T1, T2, T3, R1, R2, T5, R4, Y3, P1, N2, AF1, M2, M1	O	GV_{DD}	—

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
TSEC3_GTX_CLK	Transmit Clock Out	AE17	O	TV_{DD}	
TSEC3_RX_CLK/FEC_RX_CLK/FIFO3_RX_CLK	Receive Clock	AF17	I	TV_{DD}	1
TSEC3_RX_DV/FEC_RX_DV/FIFO3_RX_DV	Receive Data Valid	AG14	I	TV_{DD}	1
TSEC3_RX_ER/FEC_RX_ER/FIFO3_RX_ER	Receive Error	AH15	I	TV_{DD}	1
TSEC3_TX_CLK/FEC_TX_CLK/FIFO3_TX_CLK	Transmit Clock In	AF16	I	TV_{DD}	1
TSEC3_TX_EN/FEC_TX_EN/FIFO3_TX_EN	Transmit Enable	AJ18	O	TV_{DD}	1, 22
Three-Speed Ethernet Controller 4					
TSEC4_TXD[3:0]/TSEC3_TXD[7:4]/FIFO3_TXD[7:4]	Transmit Data	AD15, AC16, AC14, AB16	O	TV_{DD}	1, 5, 9
TSEC4_RXD[3:0]/TSEC3_RXD[7:4]/FIFO3_RXD[7:4]	Receive Data	AE15, AF13, AE14, AH14	I	TV_{DD}	1
TSEC4_GTX_CLK	Transmit Clock Out	AB14	O	TV_{DD}	—
TSEC4_RX_CLK/TSEC3_COL/FEC_COL/FIFO3_TX_FC	Receive Clock	AG13	I	TV_{DD}	1
TSEC4_RX_DV/TSEC3_CRS/FEC_CRS/FIFO3_RX_FC	Receive Data Valid	AD13	I/O	TV_{DD}	1, 23
TSEC4_TX_EN/TSEC3_TX_ER/FEC_TX_ER/FIFO3_TX_ER	Transmit Enable	AB15	O	TV_{DD}	1, 22
DUART					
$\overline{\text{UART\_CTS}}$[0:1]	Clear to Send	W30, Y27	I	OV_{DD}	—
$\overline{\text{UART\_RTS}}$[0:1]	Ready to Send	W31, Y30	O	OV_{DD}	5, 9
UART_SIN[0:1]	Receive Data	Y26, W29	I	OV_{DD}	—
UART_SOUT[0:1]	Transmit Data	Y25, W26	O	OV_{DD}	5, 9
I^2C Interface					
IIC1_SCL	Serial Clock	AC30	I/O	OV_{DD}	4, 20
IIC1_SDA	Serial Data	AB30	I/O	OV_{DD}	4, 20
IIC2_SCL	Serial Clock	AD30	I/O	OV_{DD}	4, 20
IIC2_SDA	Serial Data	AD29	I/O	OV_{DD}	4, 20
SerDes (x10) PCIe, SRIO					

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
N/C	No Connection	A16, A20, B16, B17, B19, B20, C17, C18, C19, D28, R31, T17, V23, W23, Y22, Y23, Y24, AA24, AB24, AC24, AC26, AC27, AC29, AD31, AE29, AJ25, AK28, AL31, AM21	—	—	17

Note:

1. All multiplexed signals are listed only once and do not re-occur. For example, LCS5/DMA_REQ2 is listed only once in the local bus controller section, and is not mentioned in the DMA section even though the pin also functions as DMA_REQ2.
2. Recommend a weak pull-up resistor (2–10 KΩ) be placed on this pin to OVDD.
4. This pin is an open drain signal.
5. This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kO pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pullup or active driver is needed.
6. Treat these pins as no connects (NC) unless using debug address functionality.
7. The value of LA[29:31] during reset sets the CCB clock to SYSCLK PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See Section 19.2, "CCB/SYSCLK PLL Ratio."
8. The value of LALE, LGPL2 and LBCTL at reset set the e500 core clock to CCB Clock PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See the Section 19.3, "e500 Core PLL Ratio."
9. Functionally, this pin is an output, but structurally it is an I/O because it either samples configuration input during reset or because it has other manufacturing test functions. This pin therefore be described as an I/O for boundary scan.
10. If this pin is configured for local bus controller usage, recommend a weak pull-up resistor (2-10 KΩ) be placed on this pin to BVDD, to ensure no random chip select assertion due to possible noise and so on.
11. This output is actively driven during reset rather than being three-stated during reset.
12. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
13. These pins are connected to the VDD/GND planes internally and may be used by the core power supply to improve tracking and regulation.
14. Internal thermally sensitive diode.
15. If this pin is connected to a device that pulls down during reset, an external pull-up is required to drive this pin to a safe state during reset.
16. This pin is only an output in FIFO mode when used as Rx Flow Control.
17. Do not connect.
18. These are test signals for factory use only and must be pulled up (100 Ω - 1 KΩ) to OVDD for normal machine operation.
19. Independent supplies derived from board VDD.
20. Recommend a pull-up resistor (~1 KΩ) be placed on this pin to OVDD.
21. The following pins must NOT be pulled down during power-on reset: DMA1_DACK[0:1], EC5_MDC, HRESET_REQ, TRIG_OUT/READY_P0/QUIESCE, MSRCID[2:4], MDVAL, ASLEEP.
22. This pin requires an external 4.7-kΩ pull-down resistor to prevent PHY from seeing a valid Transmit Enable before it is actively driven.
23. This pin is only an output in eTSEC3 FIFO mode when used as Rx flow control.
24. TSEC2_TXD[1] is used as cfg_dram_type. IT MUST BE VALID AT POWER-UP, EVEN BEFORE HRESET ASSERTION.

Figure 62 shows the PLL power supply filter circuits.

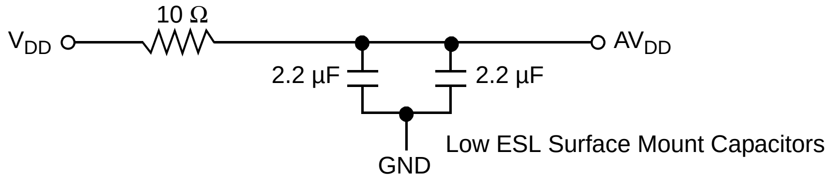
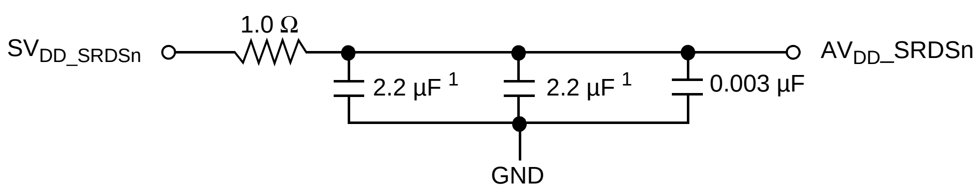


Figure 62. PLL Power Supply Filter Circuit

NOTE

It is recommended to have the minimum number of vias in the AV_{DD} trace for board layout. For example, zero vias might be possible if the AV_{DD} filter is placed on the component side. One via might be possible if it is placed on the opposite of the component side. Additionally, all traces for AV_{DD} and the filter components should be low impedance, 10 to 15 mils wide and short. This includes traces going to GND and the supply rails they are filtering.

The AV_{DD}_SRDSn signal provides power for the analog portions of the SerDesn PLL. To ensure stability of the internal clock, the power supplied to the PLL is filtered using a circuit similar to the one shown in following figure. For maximum effectiveness, the filter circuit is placed as closely as possible to the AV_{DD}_SRDSn ball to ensure it filters out as much noise as possible. The ground connection should be near the AV_{DD}_SRDSn ball. The 0.003-µF capacitor is closest to the ball, followed by the two 2.2 µF capacitors, and finally the 1 Ω resistor to the board supply plane. The capacitors are connected from AV_{DD}_SRDSn to the ground plane. Use ceramic chip capacitors with the highest possible self-resonant frequency. All traces should be kept short, wide and direct.



1. An 0805 sized capacitor is recommended for system initial bring-up.

Figure 63. SerDes PLL Power Supply Filter

NOTE

AV_{DD}_SRDSn should be a filtered version of SV_{DD}_SRDS*n*.

NOTE

Signals on the SerDesn interface are fed from the XV_{DD}_SRDS*n* power plane.

21.3 Decoupling Recommendations

Due to large address and data buses, and high operating frequencies, the device can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads.